

Dual N-Channel 20V(D-S) Enhancement Mode Mosfet

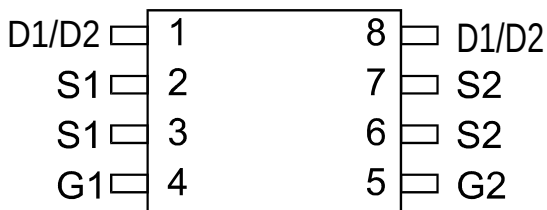
GENERAL DESCRIPTION

The 8814 Dual N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where high-side switching, and low in-line power loss are needed in a very small outline surface mount package.

PIN CONFIGURATION

(TSSOP-8)

Top View

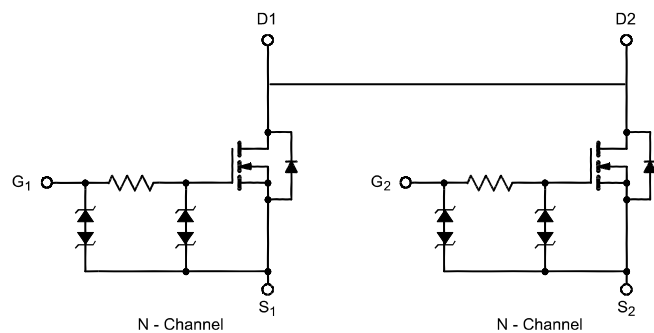


FEATURES

- $R_{DS(ON)} \leq 14.5m\Omega @ V_{GS}=4.5V$
- $R_{DS(ON)} \leq 15m\Omega @ V_{GS}=4.0V$
- $R_{DS(ON)} \leq 17m\Omega @ V_{GS}=3.1V$
- $R_{DS(ON)} \leq 20m\Omega @ V_{GS}=2.5V$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

APPLICATIONS

- Power Management in Note book
- Portable Equipment
- Battery Powered System
- Load Switch
- DSC



*Typical value by design

Ordering Information : 8814 (Green product-Halogen free)

Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ Unless Otherwise Noted)

Parameter		Symbol	Maximum	Unit
Drain-Source Voltage		V_{DSS}	20	V
Gate-Source Voltage		V_{GSS}	± 12	V
Continuous Drain Current($t_J=150^\circ\text{C}$)	$T_A=25^\circ\text{C}$	I_D	7.3	A
	$T_A=70^\circ\text{C}$		5.9	
Pulsed Drain Current		I_{DM}	29	A
Maximum Power Dissipation	$T_A=25^\circ\text{C}$	P_D	1.3	W
	$T_A=70^\circ\text{C}$		0.8	
Operating Junction Temperature		T_J	-55 to 150	$^\circ\text{C}$
Thermal Resistance-Junction to Ambient*		$R_{\theta JA}$	100	$^\circ\text{C/W}$

* The device mounted on 1in^2 FR4 board with 2 oz copper

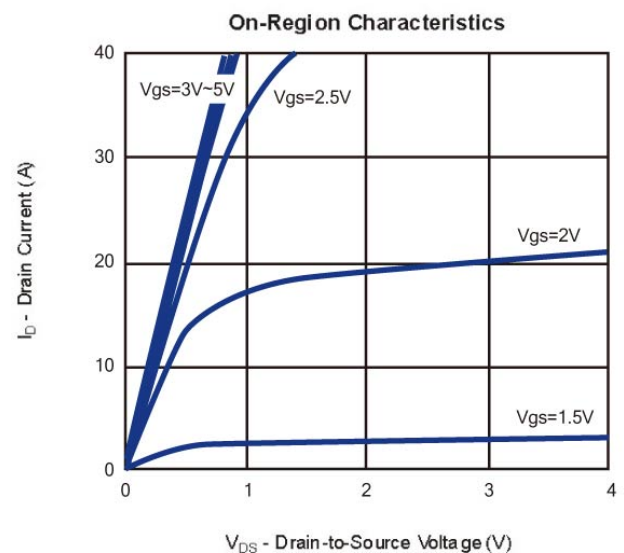
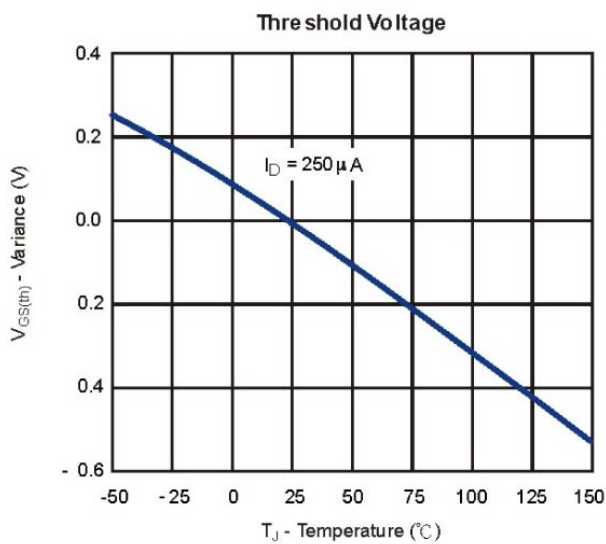
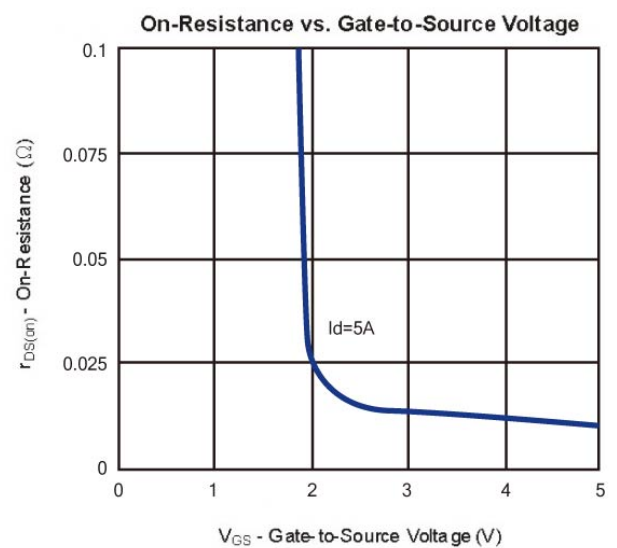
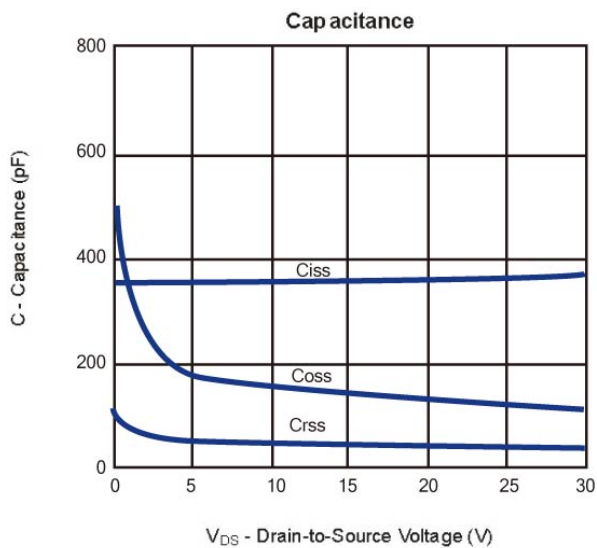
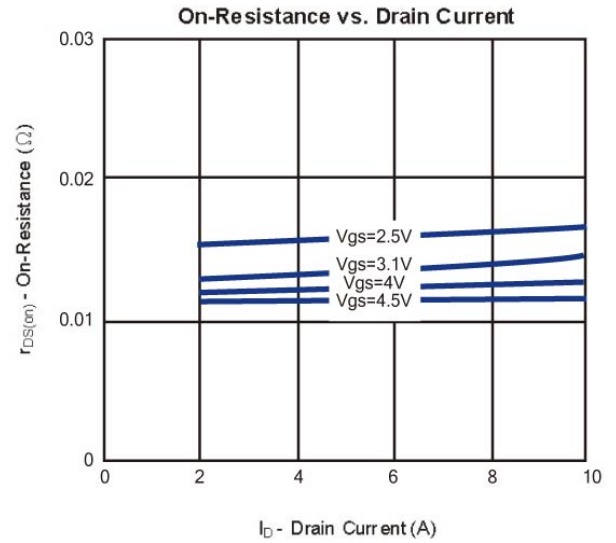
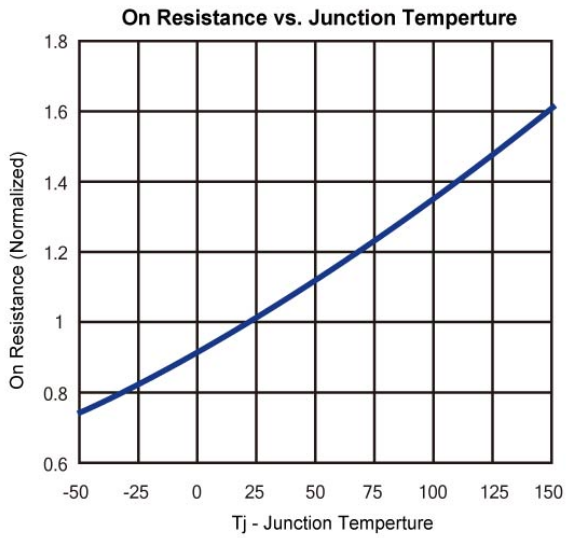
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Electrical Characteristics ($T_A=25^{\circ}\text{C}$ Unless Otherwise Specified)

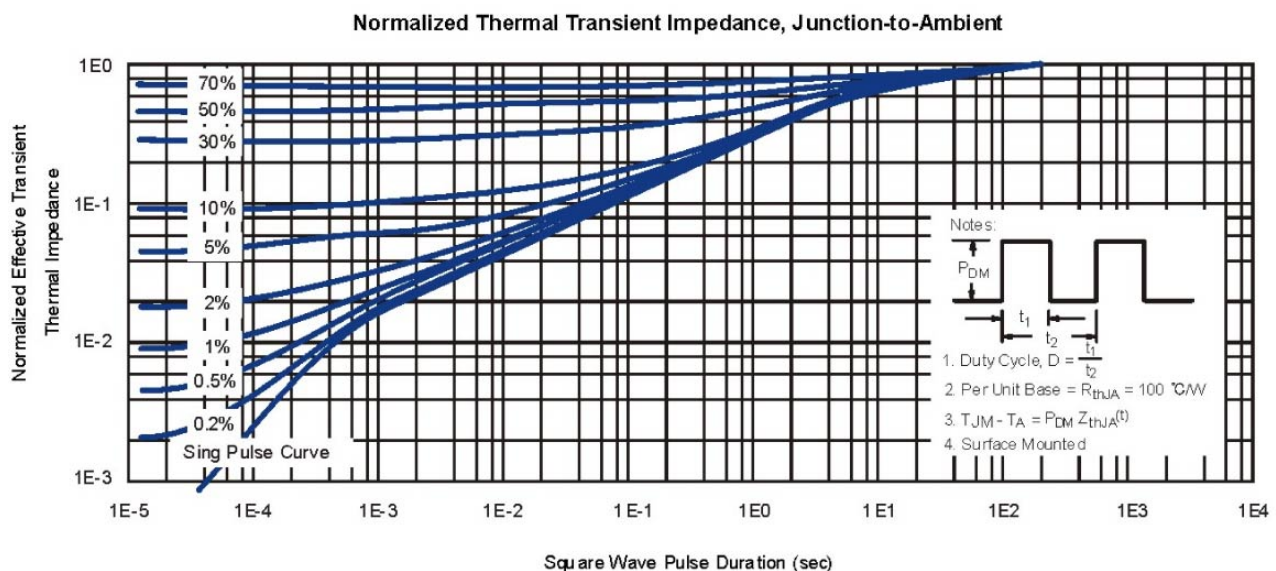
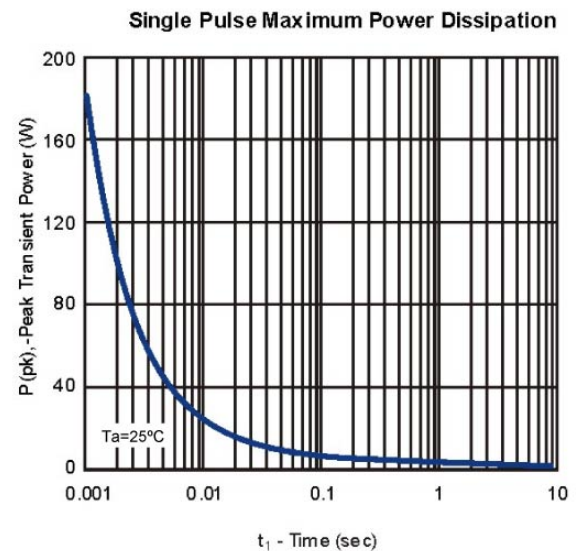
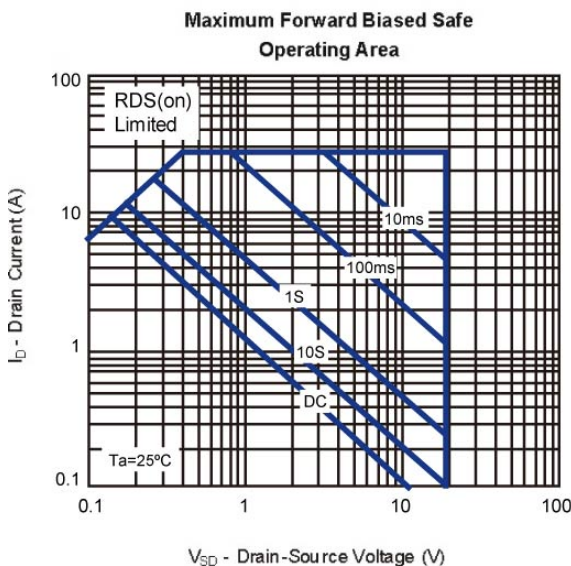
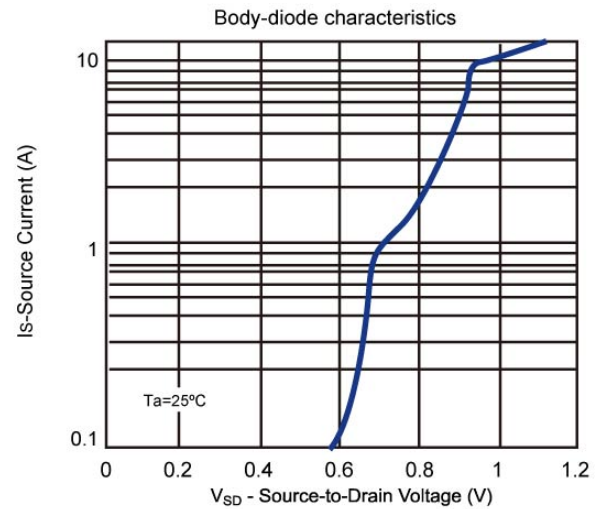
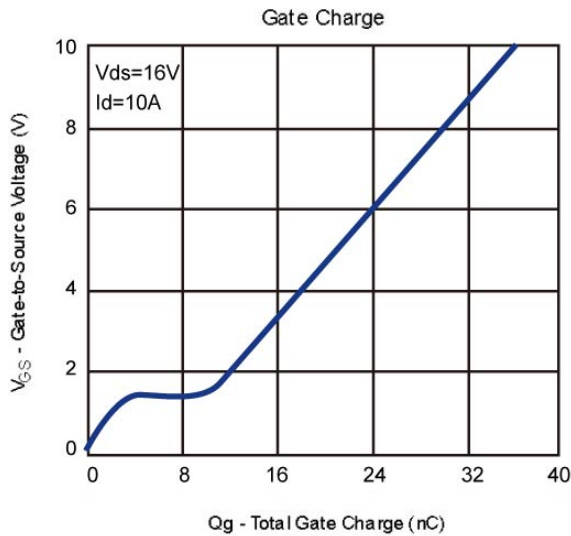
Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	20			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	0.6		1.2	V
I_{GSS}	Gate Leakage Current	$V_{DS}=0V, V_{GS}=\pm 12V$			± 10	μA
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=20V, V_{GS}=0V$			1	μA
$R_{DS(ON)}$	Drain-Source On-State Resistance ^a	$V_{GS}=4.5V, I_D=5A$		12	14.5	$m\Omega$
		$V_{GS}=4V, I_D=5A$		12.5	15	
		$V_{GS}=3.1V, I_D=5A$		13.5	17	
		$V_{GS}=2.5V, I_D=5A$		16	20	
V_{SD}	Diode Forward Voltage	$I_S=10A, V_{GS}=0V$		0.9	1.2	V
DYNAMIC						
Q_g	Total Gate Charge	$V_{DS}=16V, V_{GS}=10V, I_D=10A$		36		nC
Q_g	Total Gate Charge	$V_{DS}=16V, V_{GS}=4.5V, I_D=10A$		19		
Q_{gs}	Gate-Source Charge			3.2		
Q_{gd}	Gate-Drain Charge			7.4		
C_{iss}	Input Capacitance	$V_{DS}=25V, V_{GS}=0V, f=1MHz$		365		pF
C_{oss}	Output Capacitance			123		
C_{rss}	Reverse Transfer Capacitance			37		
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}=10V, R_L=2\Omega$ $I_D=5A, V_{GEN}=4V$ $R_G=10\Omega$		0.8		μs
t_r	Turn-On Rise Time			1.1		
$t_{d(off)}$	Turn-Off Delay Time			4.6		
t_f	Turn-Off Fall Time			2.3		

Notes: pulse test: pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$, Guaranteed by design, not subject to production testing.

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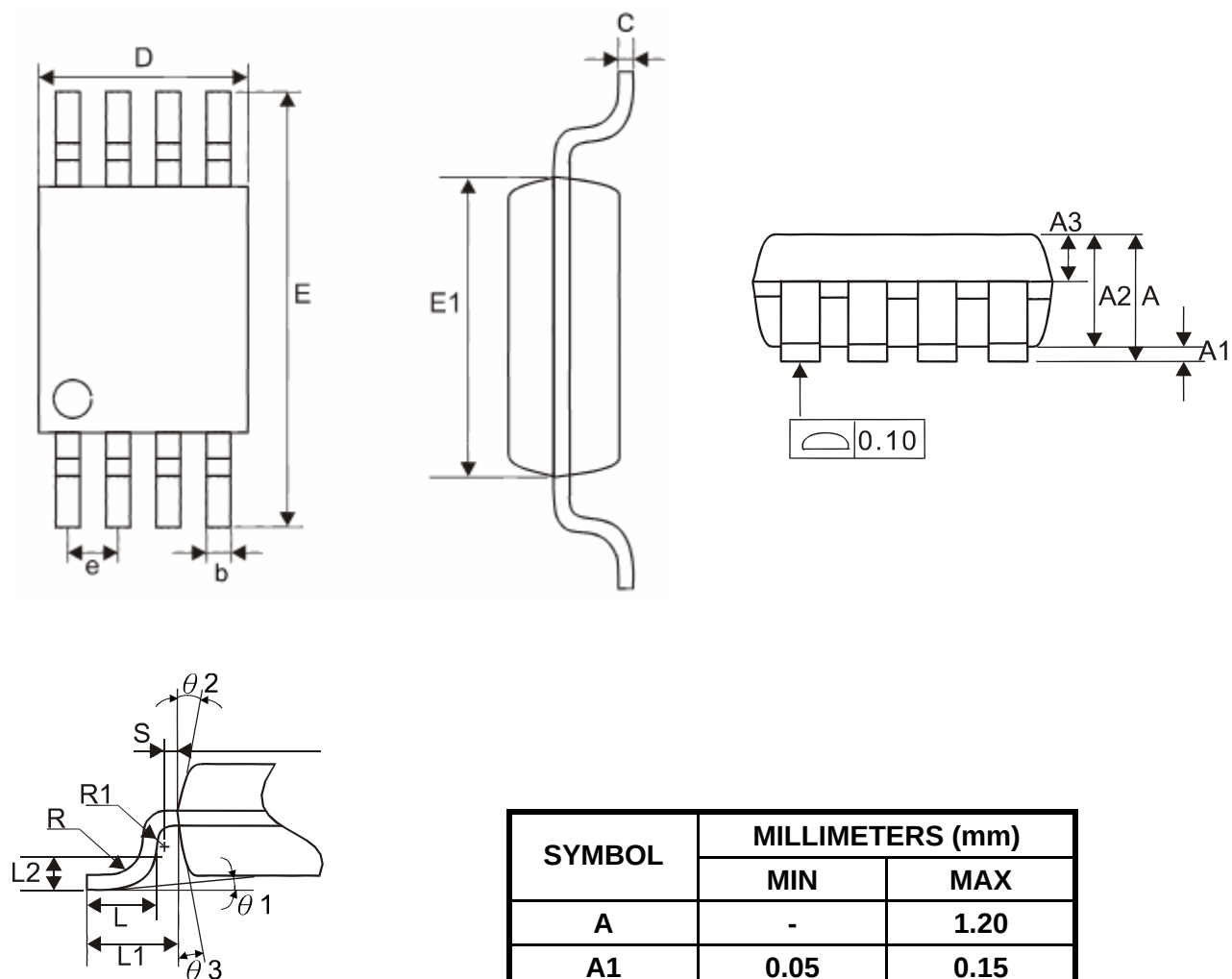
Typical Characteristics ($T_J = 25^\circ\text{C}$ Noted)

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Typical Characteristics ($T_J = 25^\circ\text{C}$ Noted)

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TSSOP-8 Package



SYMBOL	MILLIMETERS (mm)	
	MIN	MAX
A	-	1.20
A1	0.05	0.15
A2	0.90	1.05
A3	0.34	0.54
b	0.19	0.30
c	0.09	0.20
D	2.90	3.10
E	6.20	6.60
E1	4.30	4.50
e	0.65BSC	
L	0.45	0.75
L1	1.00REF	
L2	0.25BSC	
R	0.09	-